

MOSFET

OptiMOS™ Power-MOSFET, 40 V

Features

- Optimized for sychronous rectification
- 175°C rated
- Very low on-resistance R_{DS(on)}
- 100% avalanche tested
- Superior thermal resistance
- N-channel, logic level
- Pb-free lead plating; RoHS compliant
 Halogen-free according to IEC61249-2-21
- Higher solder joint reliability due to enlarged source interconnection

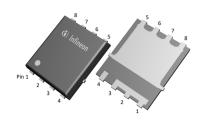
Product validation

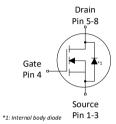
Fully qualified according to JEDEC for Industrial Applications

Table 1 **Key Performance Parameters**

Parameter	Value	Unit
$V_{ m DS}$	40	V
$R_{\mathrm{DS(on),max}}$	1.0	mΩ
I_{D}	292	A
$Q_{ m oss}$	84	nC
Q _g (0V10V)	95	nC

PG-TDSON-8









Type/Ordering Code	Package	Marking	Related Links
BSC010N04LS	PG-TDSON-8	010N04LS	-

Public

OptiMOS™ Power-MOSFET, 40 V BSC010N04LS



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1 Maximum ratings

unless otherwise specified

Table 2 Maximum ratings

Davamatav	Symphol	Values			11	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition	
Continuous drain current ¹⁾	I _D	-	-	292 206 256 181 39	А	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =4.5 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =4.5 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 K/W ²⁾	
Pulsed drain current ³⁾	I _{D,pulse}	-	-	1168	А	T _c =25 °C	
Avalanche current, single pulse ⁴⁾	I _{AS}	-	-	50	А	T _c =25 °C	
Avalanche energy, single pulse	E _{AS}	-	-	330	mJ	I_D =50 A, R_{GS} =25 Ω	
Gate source voltage ⁵⁾	V_{GS}	-20	-	20	V	-	
Power dissipation	P _{tot}	-	-	167 3.0	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 K/W ²⁾	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-55	-	175	°C	-	

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature at 25°C. For higher case temperature please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information

⁴⁾ See Diagram 13 for more detailed information

⁵⁾ The negative rating is for low duty cycle pulse occurrence. No continuous rating is implied



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			l lmit	Note / Test Condition
Parameter	Syllibot	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case	R_{thJC}	-	0.5	0.9	K/W	-
Thermal resistance, junction - case, top	ion - case, R_{thJC}		-	20	K/W	-
Device on PCB, 6 cm ² cooling area ⁶⁾	R_{thJA}	-	-	50	K/W	-

 $^{^{6)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



3 Electrical characteristics

unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Syllibol	Min.	Тур.	Мах.	Oilit	Note/ Test Condition
Drain-source breakdown voltage	$V_{(BR)DSS}$	40	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA
Gate threshold voltage	$V_{\rm GS(th)}$	1.2	-	2	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \mu{\rm A}$
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	$V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C
Gate-source leakage current	I_{GSS}	-	10	100	nA	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	1.0 0.85	1.3 1.0	mΩ	$V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =50 A $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A
Gate resistance 7) R _G		-	0.8	1.6	Ω	-
Transconductance	g_{fs}	140	270	-	S	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 50 \text{ A}$

⁷⁾ Defined by design. Not subject to production test

Table 5 Dynamic characteristics 8)

Darameter	Symbol	Values			Unit	Nieto/Tost Condition
Parameter	Symbol	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Input capacitance	C _{iss}	-	6800	9520	pF	V _{GS} =0 V, V _{DS} =20 V, <i>f</i> =1 MHz
Output capacitance	$C_{\rm oss}$	-	1900	2660	pF	V _{GS} =0 V, V _{DS} =20 V, <i>f</i> =1 MHz
Reverse transfer capacitance	C _{rss}	-	160	320	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =20 V, f =1 MHz
Turn-on delay time	$t_{\sf d(on)}$	_	10	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =30 A, $R_{\rm G,ext}$ =1.6 Ω
Rise time	t _r	-	12	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =30 A, $R_{\rm G,ext}$ =1.6 Ω
Turn-off delay time	$t_{ m d(off)}$	-	46	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =30 A, $R_{\rm G,ext}$ =1.6 Ω
Fall time	$t_{\rm f}$	_	9	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =30 A, $R_{\rm G,ext}$ =1.6 Ω

⁸⁾ Defined by design. Not subject to production test

Table 6 Gate charge characteristics 9)

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailletei	Symbol	Min.	Тур.	Мах.	Onic	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	16	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	11	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate to drain charge	$Q_{ m gd}$	-	15	21	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V



Table 6 Gate charge characteristics 9)

Parameter	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Мах.	Oilit	Note/ Test Condition
Switching charge	Q_{sw}	-	21	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total	$Q_{ m g}$	-	95	133	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate plateau voltage	$V_{ m plateau}$	-	2.4	-	V	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total	Q_{g}	-	49	69	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total, sync. FET	$Q_{g(sync)}$	-	84	-	nC	V _{DS} =0.1 V, V _{GS} =0 to 10 V
Output charge	Q _{oss}	-	84	118	nC	V _{DD} =20 V, V _{GS} =0 V

⁹⁾ See "Gate charge waveforms" for parameter definition. Defined by design. Not subject to production test

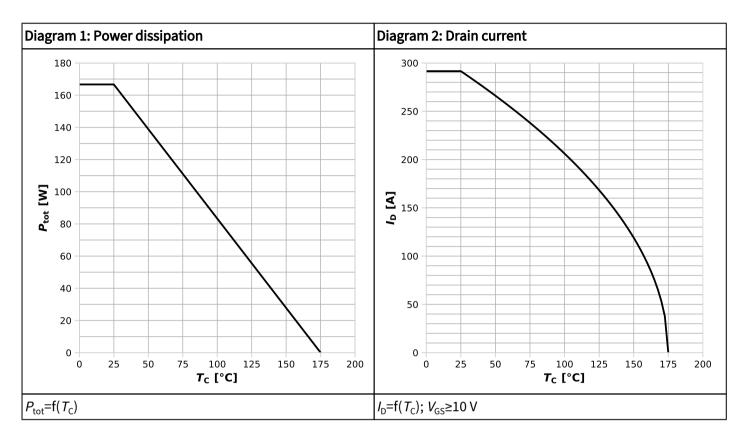
Table 7 Reverse diode

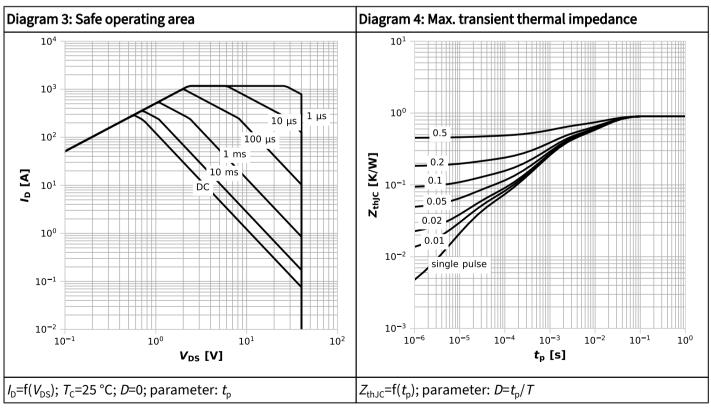
Parameter	Symbol	Values			l lmit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note/ Test Condition
Diode continuous forward current	I_{S}	-	-	167	А	<i>T</i> _C =25 °C
Diode pulse current	I _{S,pulse}	-	-	1168	А	<i>T</i> _c =25 °C
Diode forward voltage	$V_{\rm SD}$	-	0.81	1	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =50 A, $T_{\rm j}$ =25 °C
Reverse recovery time ¹⁰⁾	$t_{\rm rr}$	-	36	72	ns	$V_{\rm R}$ =20 V, $I_{\rm F}$ =50A, d $i_{\rm F}$ /d t =400 A/ μ s
Reverse recovery charge ¹⁰⁾	$Q_{\rm rr}$	-	50	-	nC	$V_{\rm R}$ =15 V, $I_{\rm F}$ = $I_{\rm S}$, d $I_{\rm F}$ /d I =400 A/ μ s

 $^{^{10)}}$ Defined by design. Not subject to production test

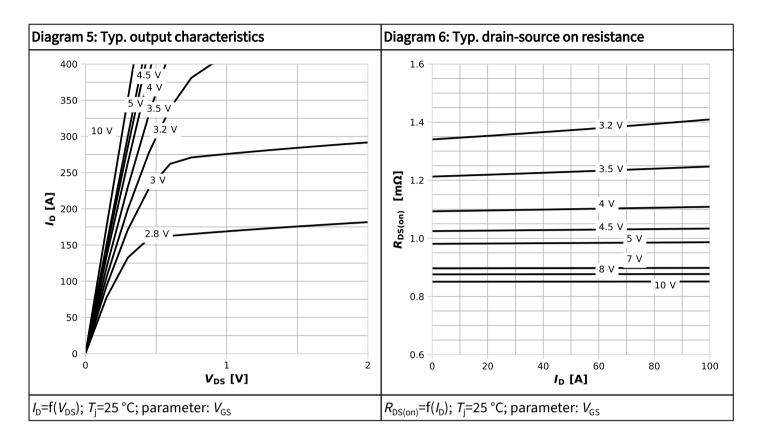


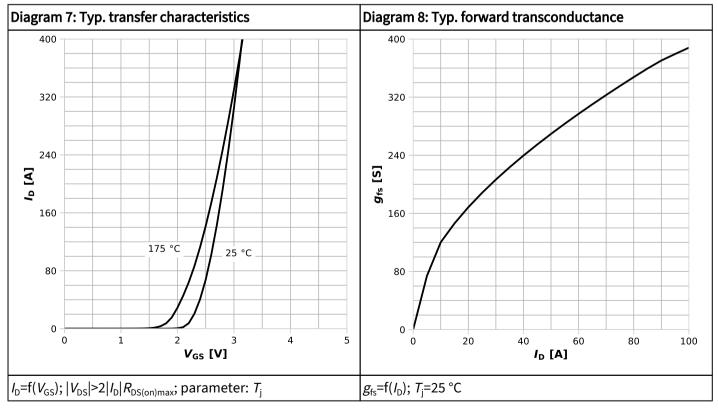
4 Electrical characteristics diagrams



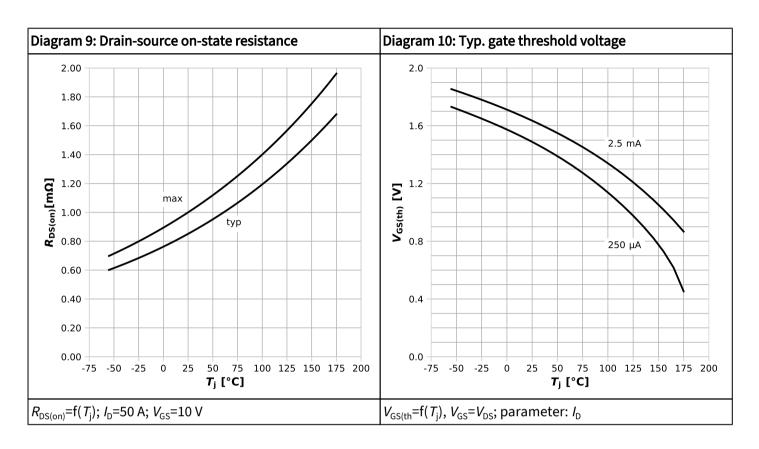


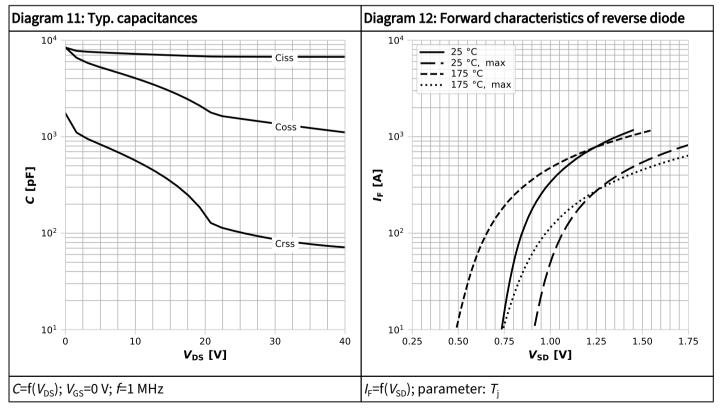




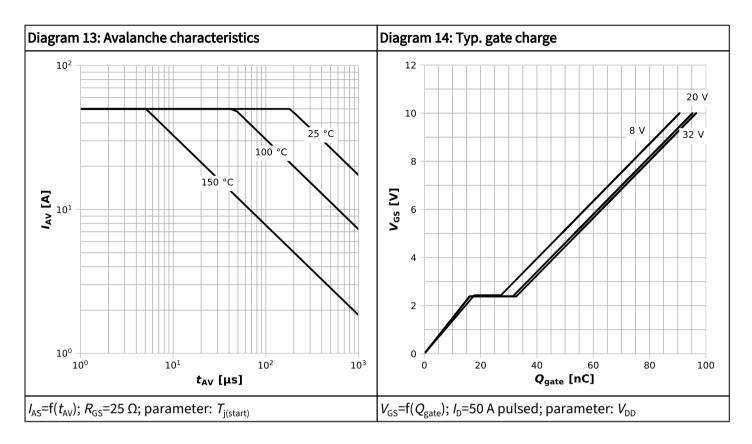


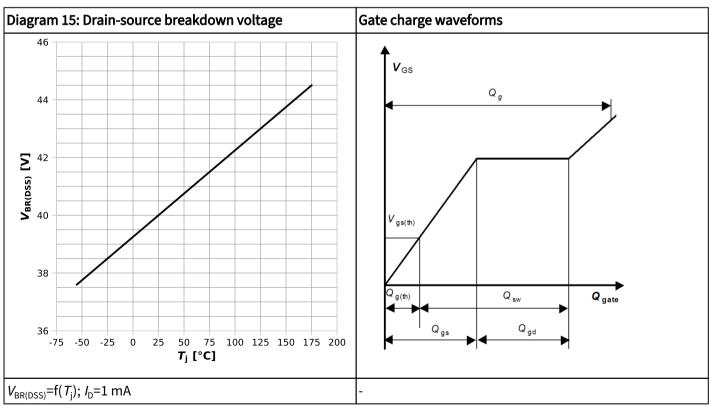














5 Package Outlines

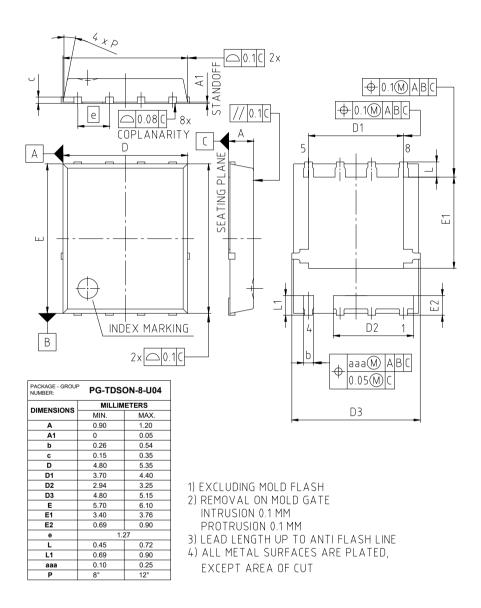


Figure 1 Outline PG-TDSON-8, dimensions in mm



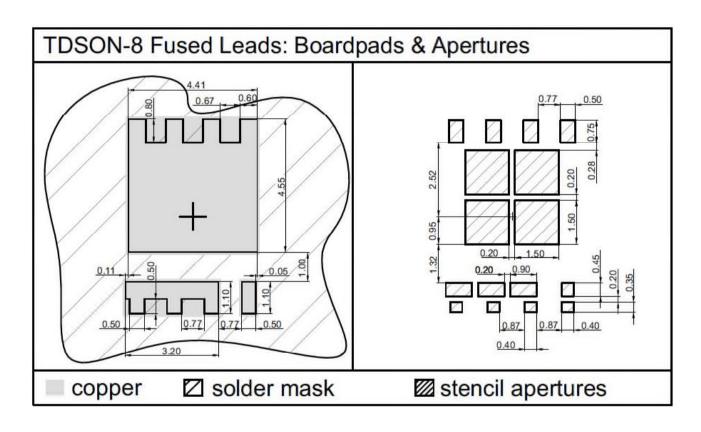


Figure 2 Outline PG-TDSON-8, dimensions in mm



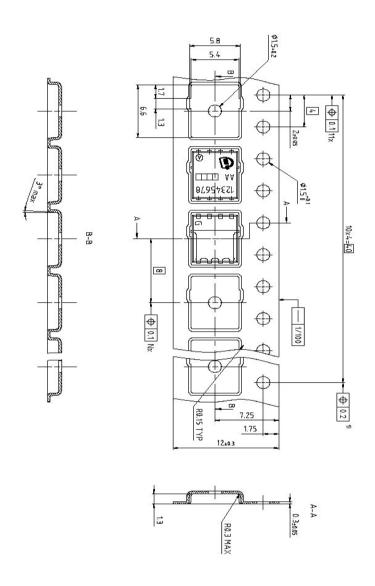


Figure 3 Outline PG-TDSON-8, dimensions in mm



Revision History

BSC010N04LS

Revision 2024-06-11, Rev. 2.5

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.2	2014-06-27	Rev. 2.2
2.3	2019-09-27	Update package drawings
2.4	2020-03-13	Update current rating
2.5	2024-06-11	Upgrade Operating and storage temperature max to 175°C. Update drawings in section 5 Package Outlines. Production validation added on page1.Updated foot notes.

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